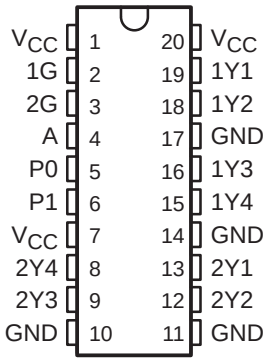
CDC340
1-LINE TO 8-LINE CLOCK DRIVER

SCAS332B – DECEMBER 1992 – REVISED MAY 1997

- **Low Output Skew, Low Pulse Skew for Clock-Distribution and Clock-Generation Applications**
- **TTL-Compatible Inputs and Outputs**
- **Distributes One Clock Input to Eight Outputs**
- **Distributed V_{CC} and Ground Pins Reduce Switching Noise**
- **High-Drive Outputs (–48-mA I_{OH}, 48-mA I_{OL})**
- **State-of-the-Art *EPIC*-II*B*™ BiCMOS Design Significantly Reduces Power Dissipation**
- **Package Options Include Plastic Small-Outline (DW) and Shrink**

DW PACKAGE
(TOP VIEW)



description

The CDC340 is a high-performance clock-driver circuit that distributes one (A) input signal to eight (Y) outputs with minimum skew for clock distribution. Through the use of the control pins (1G and 2G), the outputs can be placed in a high state regardless of the A input.

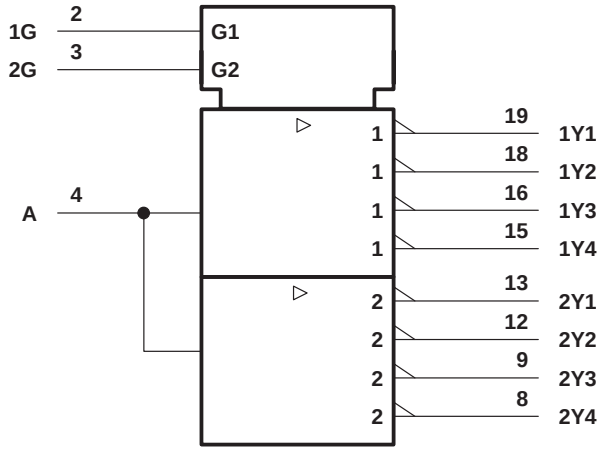
The propagation delays are adjusted at the factory using the P0 and P1 pins. These pins are not intended for customer use and should be strapped to GND.

The CDC340 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

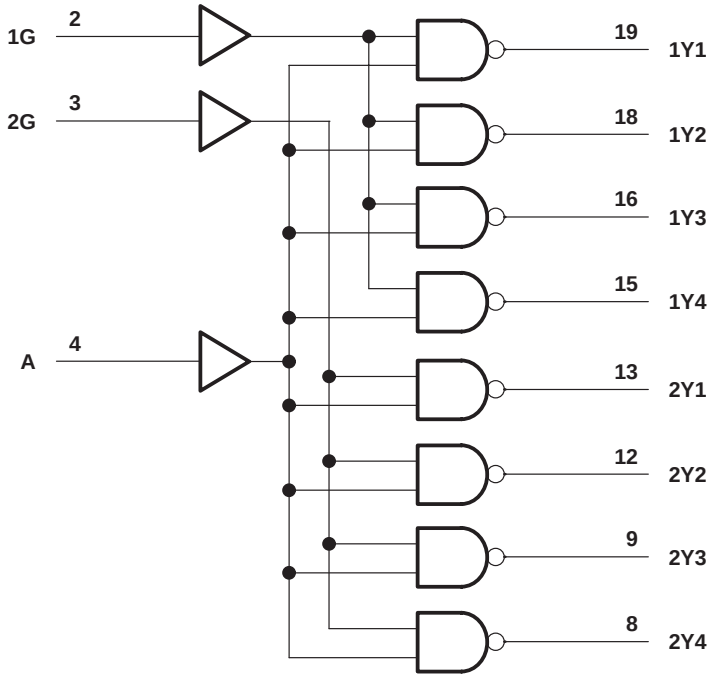
INPUTS			OUTPUTS	
1G	2G	A	1Y1–1Y4	2Y1–2Y4
X	X	L	H	H
L	L	H	H	H
L	H	H	H	L
H	L	H	L	H
H	H	H	L	L

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . . –0.5 V to 7 V
Input voltage range, V_I (see Note 1) . . . . . –0.5 V to 7 V
Voltage range applied to any output in the high state or power-off state,
V_O (see Note 1) . . . . . –0.5 V to V_{CC} + 0.5 V
Current into any output in the low state, I_O . . . . . 96 mA
Input clamp current, I_{IK} (V_I < 0) . . . . . –18 mA
Maximum power dissipation at T_A = 55°C (in still air) (see Note 2): DW package . . . . . 1.6 W
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* Application Note in the *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002.

recommended operating conditions (see Note 3)

			MIN	MAX	UNIT
V_{CC}	Supply voltage		4.75	5.25	V
V_{IH}	High-level input voltage		2		V
V_{IL}	Low-level input voltage			0.8	V
V_I	Input voltage		0	V_{CC}	V
I_{OH}	High-level output current			–48	mA
I_{OL}	Low-level output current			48	mA
f_{clock}	Input clock frequency	One output back loaded		80	MHz
		Both output banks loaded		40	
T_A	Operating free-air temperature		0	70	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS			T_A = 25°C			MIN	MAX	UNIT
				MIN	TYP‡	MAX			
V_{IK}	V_{CC} = 4.75 V,	I_I = –18 mA				–1.2		–1.2	V
V_{OH}	V_{CC} = 4.75 V,	I_{OH} = – 3 mA		2.5			2.5		V
	V_{CC} = 5 V,	I_{OH} = – 3 mA		3			3		
	V_{CC} = 4.75 V,	I_{OH} = – 48 mA		2			2		
V_{OL}	V_{CC} = 4.75 V,	I_{OL} = 48 mA						0.5	V
I_I	V_{CC} = 5.25 V,	V_I = V_{CC} or GND				±1		±1	µA
I_O§	V_{CC} = 5.25 V,	V_O = 2.5 V		–50	–100	–200	–50	–200	mA
I_{CC}	V_{CC} = 5.25 V, V_I = V_{CC} or GND	I_O = 0,	Outputs high		2			3.5	mA
			Outputs low		24			33	
C_i	V_I = 2.5 V or 0.5 V				3				pF

‡ All typical values are at V_{CC} = 5 V.
§ No more than one output should be tested at a time, and the duration of the test should not exceed one second.

switching characteristics, C_L = 50 pF (see Figure 1 and Figure 2)

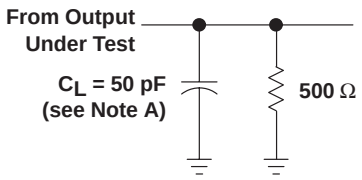
PARAMETER		FROM (INPUT)	TO (OUTPUT)	V_{CC} = 5 V, T_A = 25°C			V_{CC} = 4.75 V to 5.25 V, T_A = 0°C to 70°C		UNIT
				MIN	TYP	MAX	MIN	MAX	
t_{PLH}	Propagation delay time, low-to-high level	A	Y	3.4		4.5	3	4.8	ns
t_{PHL}	Propagation delay time, high-to-low level			3.2		4.3	2.8	4.7	
t_{PLH}	Propagation delay time, low-to-high level	G	Y	2		3.8	2	4	ns
t_{PHL}	Propagation delay time, high-to-low level			2		3.8	2	4	
$t_{sk(o)}$	Skew time, output	A	Y		0.3	0.5		0.6	ns
$t_{sk(p)}$	Skew time, pulse				0.6	0.8		0.9	
$t_{sk(pr)}$	Skew time, process					1.1		1.1	
t_r	Rise time	A	Y					1.5	ns
t_f	Fall time	A	Y					1.5	ns

t_{pd} performance information relative to V_{CC} and temperature variation (see Note 4)

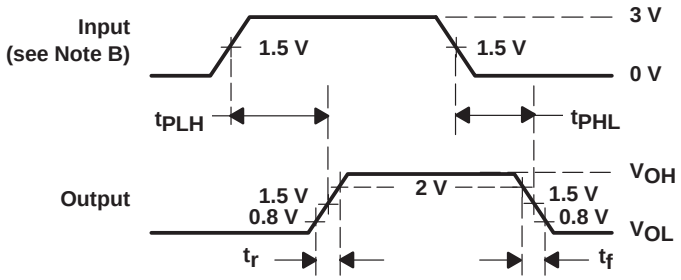
PARAMETER		Δ change
$\Delta t_{PLH(TA)}$†	Temperature drift of t_{PLH} from 0°C to 70°C	–53 ps/10°C
$\Delta t_{PHL(TA)}$†	Temperature drift of t_{PHL} from 0°C to 70°C	–58 ps/10°C
$\Delta t_{PLH(VCC)}$‡	V_{CC} drift of t_{PLH} from 4.75 V to 5.25 V	43 ps/100 mV
$\Delta t_{PHL(VCC)}$‡	V_{CC} drift of t_{PHL} from 4.75 V to 5.25 V	–33 ps/100 mV

† Virtually independent of V_{CC}
‡ Virtually independent of temperature
NOTE 4: The data extracted is from a wide range of characterization material.

PARAMETER MEASUREMENT INFORMATION



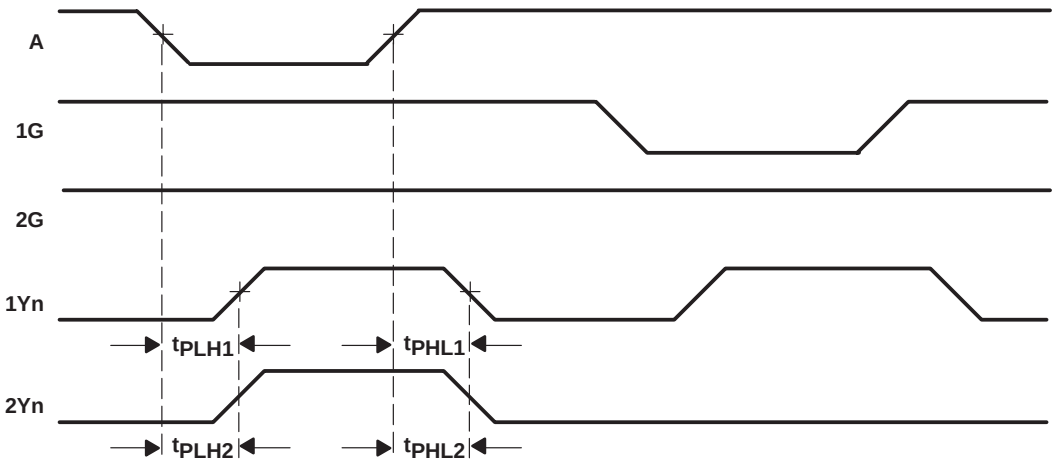
LOAD CIRCUIT



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.

Figure 1. Load Circuit and Voltage Waveforms



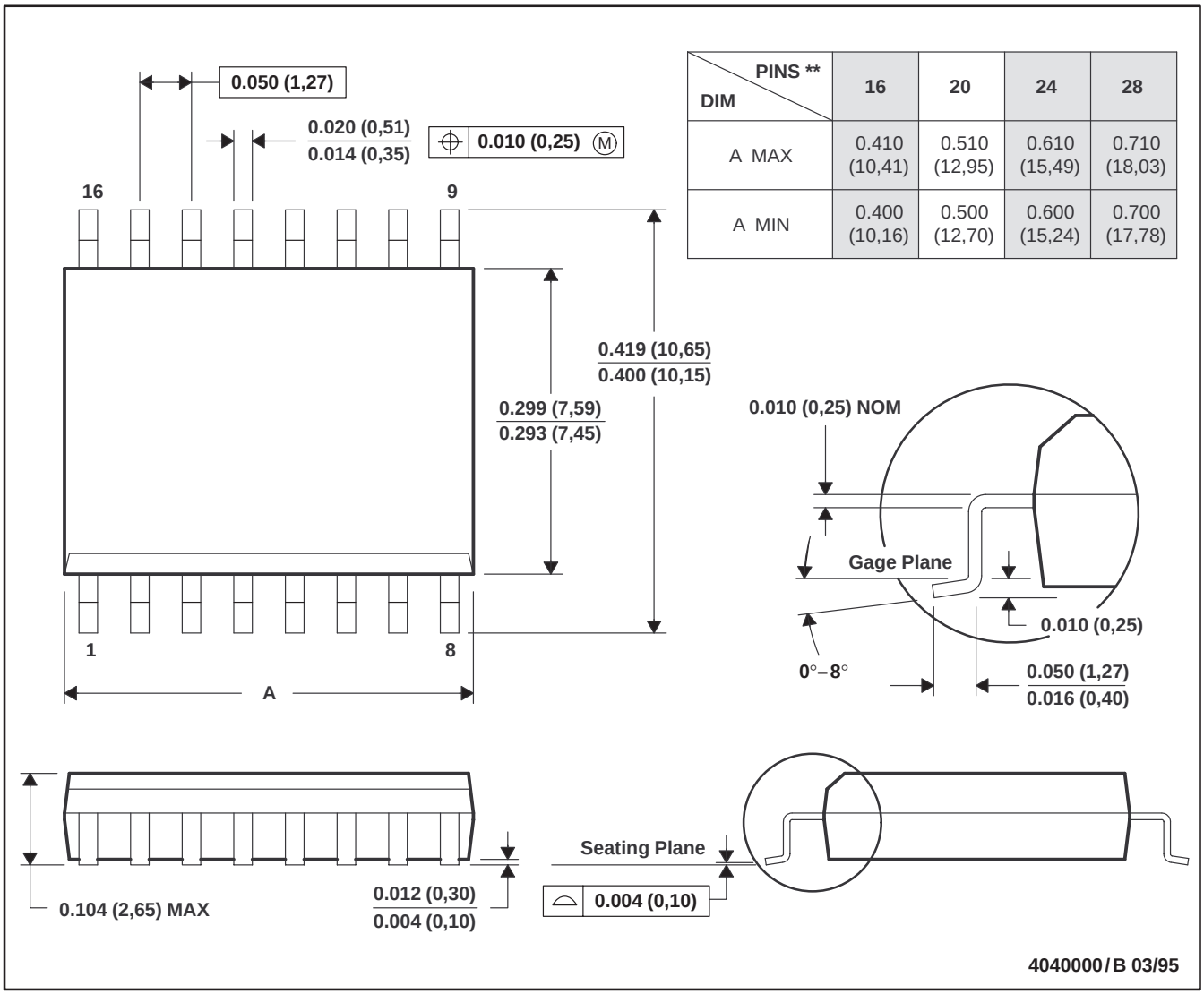
NOTES: A. Output skew, $t_{sk(o)}$, is calculated as the greater of:
– The difference between the fastest and slowest of t_{PLHn} (n = 1, 2)
– The difference between the fastest and slowest of t_{PHLn} (n = 1, 2)
B. Pulse skew, $t_{sk(p)}$, is calculated as the greater of | $t_{PLHn} - t_{PHLn}$ | (n = 1, 2).
C. Process skew, $t_{sk(pr)}$, is calculated as the greater of:
– The difference between the fastest and slowest of t_{PLHn} (n = 1, 2) across multiple devices under identical operating conditions
– The difference between the fastest and slowest of t_{PHLn} (n = 1, 2) across multiple devices under identical operating conditions

Figure 2. Waveforms for Calculation of $t_{sk(o)}$, $t_{sk(p)}$, $t_{sk(pr)}$

MECHANICAL INFORMATION

DW (R-PDSO-G)** **PLASTIC SMALL-OUTLINE PACKAGE**

16 PIN SHOWN



DIM \ PINS **	16	20	24	28
A MAX	0.410 (10,41)	0.510 (12,95)	0.610 (15,49)	0.710 (18,03)
A MIN	0.400 (10,16)	0.500 (12,70)	0.600 (15,24)	0.700 (17,78)

NOTES: A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
D. Falls within JEDEC MS-013

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